

<b>Notice of References Cited</b>	Application/Control No. 10/648,029	Applicant(s)/Patent Under Reexamination KLEDZIK ET AL.	
	Examiner Nathan W. Ha	Art Unit 2814	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,828,666 B1	12-2004	Herrell et al.	257/691
	B	US-2003/0122240 A1	07-2003	Lin et al.	257/686
	C	US-6,222,739 B1	04-2001	Bhakta et al.	361/790
	D	US-2003/0168725 A1	09-2003	Warner et al.	257/686
	E	US-2003/0201526 A1	10-2003	Bolken et al.	257/686
	F	US-2003/0137808 A1	07-2003	Kledzik et al.	361/704
	G	US-5,754,408	05-1998	Derouiche, Nour Eddine	361/773
	H	US-5,061,990	10-1991	Arakawa et al.	257/676
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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